

Search Notes

Application/Control No.

10/510,591

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

KLOEN ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E23.054, E23.124, 678 & 787	11/10/2006	C.C.
257	700 & 781	11/10/2006	C.C.
257	786 & 738	11/10/2006	C.C.
257	737 & 684	11/10/2006	C.C.
438	124 & 106	11/10/2006	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
As same	as above	11/10/2006	C.C.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	11/10/2006	C.C.